

**Search Notes**

Application/Control No.

10/500,581

Examiner

Nguyen N. Hanh

Applicant(s)/Patent under  
Reexamination

TAKENAKA ET AL.

Art Unit

2834

**SEARCHED**

Class	Subclass	Date	Examiner
310	52	7/25/2005	HN
310	54	7/25/2005	HN
310	58	7/25/2005	HN
310	64	7/25/2005	HN
update search	All	11/28/05	HN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
310	64	11/28/05	HN

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PG Pub Text search See interference search print out	11/28/05	HN